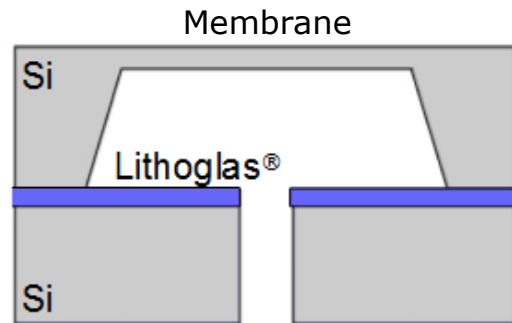


# Next Generation Pressure Sensor

## Conventional Structure



## Next Generation Structure

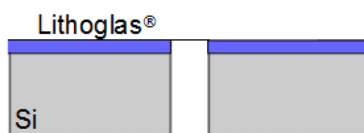


Example: gauge pressure sensor

## Lithoglas® Silicon-to-Silicon Bond

- Bulk glass is replaced by glass coated silicon
- Lower signal drift through matching CTE and Young's modulus
- Si offers smaller tolerances and less noise
- Smaller and more precise structures (holes) in silicon
- Higher flexural strength
- Thinner device, smaller footprint
- Robust anodic bond instead of direct Si-Si fusion
- Lower bond voltages ( $< 100$  V) compared to bulk glass bonding

### Design Rules:



typ. application: absolute or differential pressure sensor

*Wafer Material*

*Glass Film Thickness*

*Wafer Size (Diameter)*

*Wafer Thickness*

*Through Hole Diameter*

*Side Wall Angle of Hole*

*Through Hole Pitch*

*Through Hole Shape*

*Silicon with Thin Glass Coating*

*3 - 5  $\mu\text{m}$  (on silicon dioxide layer)*

*Semi Std. 100 mm, 150 mm, 200 mm*

*$\geq 200 \mu\text{m}$ ,  $\leq 3000 \mu\text{m}$*

*$\geq 200 \mu\text{m}$  (upon request)*

*$90^\circ$*

*$\geq 500 \mu\text{m}$*

*circular*